

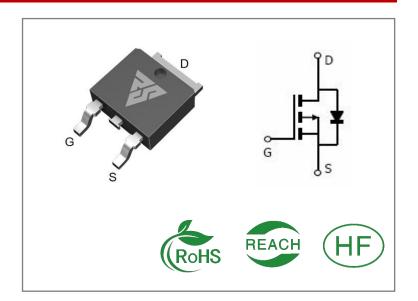
ID	R _{DS} (ON)(Typ)	VDSS
-65A	7.1mΩ	-30V

Applications:

- Load Switch
- PWM Applications
- Power Managment

Features:

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability



Ordering Information

Part Number	Package	Marking	Packing	Qty.
RS30P65D	TO-252	RS30P65D	Tape&reel	2500 PCS

Absolute Maximun Ratings Tc= 25°C unless otherwise specified

Symbol	Parameter	RS30P65D	Units
VDSS	Drain-to-Source Voltage	-30	V
ID	Continuous Drain Current TC=25℃	-65	
ID	Continuous Drain Current TC=100℃	-45	А
IDM	Pulsed Drain Current (Note*1)	-260	
PD	Power Dissipation	83	W
VGS	Gate- to- Source Voltage	±25	V
EAS	Avalanche Engergy VG=-10V, VDD =30V, RG = 25 Ω ,TC=25 $^{\circ}$ C	500	mJ
	Maximum Temperature for Soldering		
TL TPKG	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds	300 260 °C	
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 175	
ESD	HBN JESD22-A114	1000	V
	CDM JESD22-C101	1000	V

^{*} Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the Absolute Maximum Ratings" Table may cause permanent damage to the device.



Thermal Resistance

Symbol	Parameter	RS30P65D	Units	Test Conditions
RθJC	Junction-to-Case	1.8	°C/W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 1 5 0 $^{\circ}\mathrm{C}$

OFF Characteristics TJ= 25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown	-30			V	VGS=0V
BVD33	Voltage	-30			V	ID=250μA
IDSS	Drain- to- Source Leakage			-1		VDS=-30V
נטו	Current	-1	μΑ	VGS=0V		
	Gate- to- Source Forward			100		VGS=25V
IGSS	Leakage			100	5 Λ	VDS=0V
1033	Gate- to- Source Reverse			-100	nA	VGS=-25V
	Leakage			-100		VDS=0V
GFS	Forward Transconductance	20	28		S	VDS=-5V
GF3	Forward Transconductance	20	20)	ID=-10A

ON Characteristics TJ=25 °C unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
		7.1	9.2	mΩ	VGS=-10V	
DDS(on)	RDS(on) Static Drain- to- Source On- Resistance(Note*2)		/.1	7.2	11152	ID=-20A
KD3(011)			10	17	m2 ()	VGS=-5V
			10	16	mΩ	ID=-15A
VGS	Gate Threshold Voltage	-1.0	-1.8	-3	\/	VGS=VDS
(TH)	Gate Tiffeshold Voltage	-1.0	-1.0	-3	V	ID=250μA

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time		16			\/DC 45\/
trise	Rise Time		14			VDS=-15V VGS=-10V
td(OFF)	Turn- OFF Delay Time		50		nS	ID=-1A RG=2.5Ω
tfall	Fall Time		22			RG-2.312



Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
Ciss	Input Capacitance		3570			VGS=0V
Coss	Output Capacitance		435		pF	VDS=-15V
Crss	Reverse Transfer Capacitance		175			f=1MHz
Qg	Total Gate Charge		58			VDS=-15V
Qgs	Gate- to- Source Charge		9		nC	ID=-10A
Qgd	Gate-to-Drain(" Miller") Charge		14			VGS=-10V

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Test Conditions
ISD	Source-Drain Current(BodyDiode)			-50	Α	Integral pn- diode in MOSFET
VSD	Diode Forward Voltage			-1.2	V	IS=-10A,VGS=0V

Notes:

- * 1. Repetitive rating, pulse width limited by maximum junction temperature.
- * 2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 0.5%



Typical Feature Curve

Figure 1. Power Dissipation

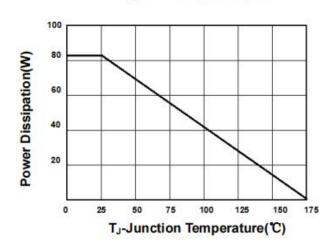


Figure3. Output Characteristics

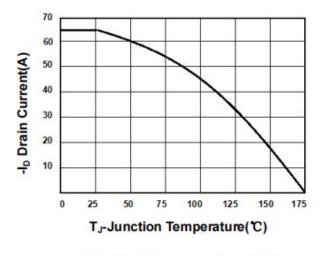
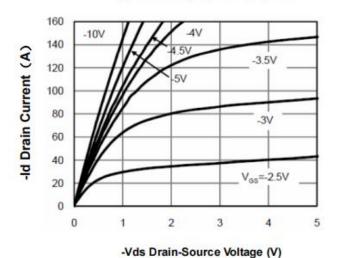


Figure 2. Drain Current

Figure4. Transfer Characteristics



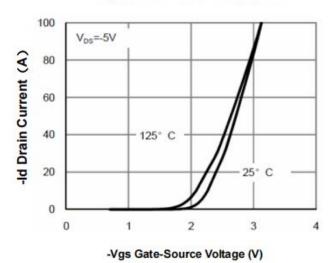




Figure5. Capacitance

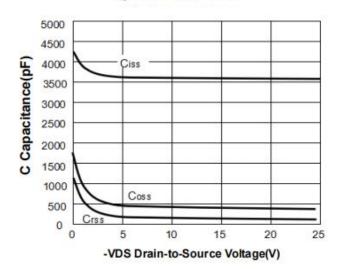


Figure 6. RDS(ON) vs Junction Temperature

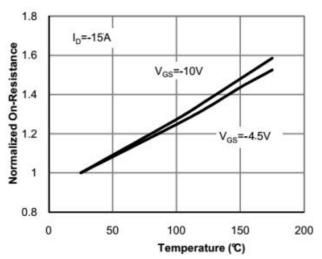


Figure 7. Max BV_{DSS} vs Junction Temperature

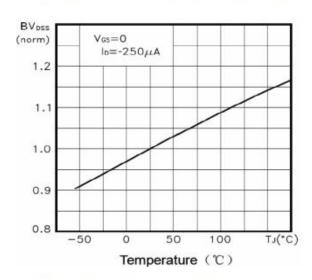


Figure8. V_{GS(th)} vs Junction Temperature

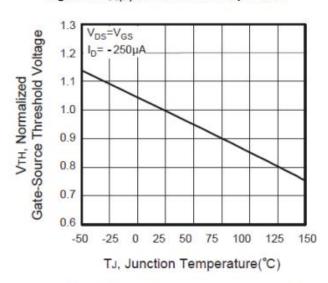


Figure9. Gate Charge Waveforms

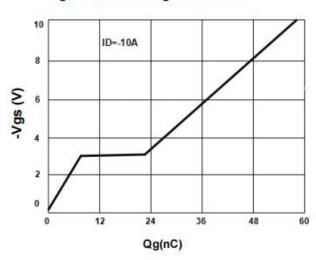
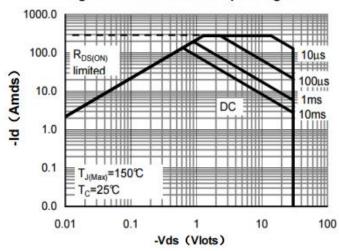


Figure 10. Maximum Safe Operating Area

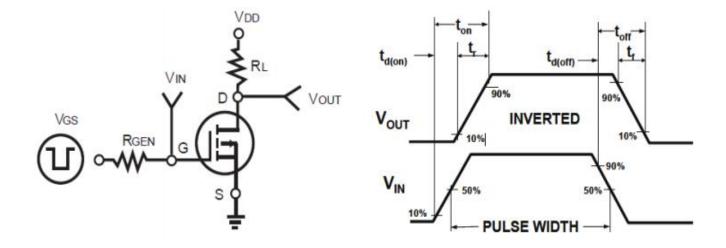




10 In descending order D=T_{on}/T Z_{e,C} Normalized Transient Thermal Resistance D=0.5, 0.3, 0.1, 0.05, 0.02, 0.01, single pulse T_{J,PK}=T_C+P_{DM}-Z_{BJC}-R_{BJC} 1 0.1 Single Pulse 0.01 0.00001 0.0001 0.001 0.01 0.1 1 10 Pulse Width (s)

Figure 11. Normalized Maximum Transient Thermal Impedance

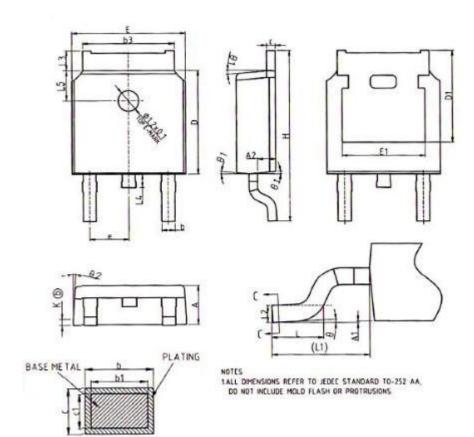
Test Circuits and Waveforms





Package outline drawing(TO-252 Unit: mm)

SECTION C-C



Ť	COMMON L	IMENSIO mm	no .		
SYMBOL	MIN	NOM	MAX		
A	2.20	2.30	2.38		
A1	0.00	-	0.10		
A2	0.97	1.07	1, 17		
b	0.72	0.78	0.85		
bl	0.71	0,76	0.81		
b3	5. 23	5, 33	5.46		
c	0.47	0.53	0.58		
cl	0.46	0.51	0.56		
D	6,00	6.10	6,20		
DI		5. 30REF	7001201		
E	6.50	6.60	6.70		
E1	4.70	4.83	4.92		
e	- 100	2. 286BSC	III AND CO		
н	9.90	10, 10	10.30		
L	1, 40	1.50	1,70		
LI	Charles Control	2. 90REF			
1.2		0, 51BSC			
L3	0.90	-	1.25		
1.4	0.60	0.80	1,00		
L5	1,70	1.80	1,90		
0	0.	+	8*		
01	5*	7*	9.		
9.2	5*	7*	9.		
K		0. 10REF			



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